## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination	
10046512	HAMASAKA ET AL.	
Examiner	Art Unit	
Tekle, Daniel	2633	

SEARCHED					
Class	Subclass	Date	Examiner		
386	95	07/05/2006	DT		
386	126	07/05/2006	DT		
SEARCH UPDATED		05/16/07	D.T.		

SEARCH NOTES				
Search Notes	Date	Examiner		
USPAT, US-PGPUB, USOCR, EPO, JPO, DERWENT, IBM_TDB	07/05/06	D.T.		
INVENTER SEARCH, NPL (ACM DIGITAL LIBRARY, CITESEER)	07/05/06	D.T.		
SEARCH QUERY (managment same (user near3 define or entry) same (receiver same analyzer)	05/17/07	D.T.		

INTERFERENCE SEARCH						
Class		Subclass	Date	Examiner		
386	126		05/16/07	D.T.		